

Model 2450/2460/2461 Graphical SourceMeter® SMU Instruments

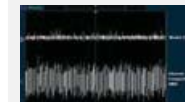


30-SECOND SELL

“These instruments offer the benefits of I-V systems, curve tracers, and semiconductor analyzers at a fraction of the cost. Their touchscreen graphical user interface enables engineers and scientists to learn faster, work smarter, and invent easier.”

PRODUCT HIGHLIGHTS

- 4-quadrant design simultaneously sources and measures voltage, current, and resistance
- Advanced, five-inch touchscreen user interface with multi-point, pan-pinch-zoom-swipe operation
- Graphical interface provides I-V curve tracing functionality
- Lower current and voltage measurements ranges (100nA, 10nA, 20mV) on Model 2450
- High current and high power ranges (7A, 100W DC, Model 2460; 10A, 1000W Pulse, Model 2461)
- Front panel banana jack inputs and rear panel connections (triaxial connectors on 2450, mass terminated screw terminal on 2460/2461)
- GPIB, LAN (LXI), USB interfaces



With significantly lower wideband noise than its closest competitor, the 2450 is the perfect solution for I-V testing of next-generation devices.

MODEL	STOCK CODE	CURRENT MAX / MIN	VOLTAGE MAX / MIN	POWER
2450	2324804	1.000000A / 10.00000nA	200.0000V / 20.00000mV	20W
2450-NFP (with No Front Panel)	NIC			
2450-RACK (without Handle)	NIC			
2450-NFP-RACK (with No Front Panel or Handle)	NIC			
2460	2449573	7.000000A / 1.000000μA	100.0000V / 200.0000mV	100W
2460-NFP (with No Front Panel)	NIC			
2460-RACK (without Handle)	NIC			
2460-NFP-RACK (with No Front Panel or Handle)	NIC			
2461	2510757	10.00000A / 1.000000μA	100.0000V / 200.0000mV	1000W
2461-NFP (with No Front Panel)	NIC			
2461-RACK (without Handle)	NIC			
2461-NFP-RACK (with No Front Panel or Handle)	NIC			

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RECOMMENDED ACCESSORIES

5805	Kelvin (4-Wire) Spring-Loaded Probes	2131246
5808	Low Cost Single-pin Kelvin Probe Set	2131247
8607	2-Wire, 1000V Banana Cables, 1m (3.3 ft.)	NIC
CS-1616-3	Safety Interlock Mating Connector	2460268

RECOMMENDED SERVICE

24XX-3Y-EW	1-year factory warranty extended to 3 years from date of shipment	NIC
24XX-5Y-EW	1-year factory warranty extended to 5 years from date of shipment	NIC
C/24XX-3Y-17025	KeithleyCare® 3-year ISO 17025 Calibration Plan	NIC
C/24XX-3Y-DATA	KeithleyCare® 3-year Calibration w/Data Plan	NIC
C/24XX-3Y-STD	KeithleyCare® 3-year Std. Calibration Plan	NIC
C/24XX-5Y-17025	KeithleyCare® 5-year ISO 17025 Calibration Plan	NIC
C/24XX-5Y-DATA	KeithleyCare® 5-year Calibration w/Data Plan	NIC
C/24XX-5Y-STD	KeithleyCare® 5-year Std. Calibration Plan	NIC

SHIPS WITH PRODUCT

- 8608 High Performance Test Leads
- 2460-KIT Rear Panel Mating Mass Terminated Screw Connector (Model 2460/2461 ONLY)
- USB-B-1 USB Cable, Type A to Type B, 1m (3.3 ft)
- CS-1616-3 Safety Interlock Mating Connector
- CA-180-3A TSP-Link®/Ethernet Cable
- Documentation CD
- QuickStart Guide
- Test Script Builder Software (available at www.tek.com)
- KickStart Startup Software (available at www.tek.com)
- LabVIEW® and IVI Drivers (available at www.tek.com)


ANOTHER PRODUCT FOR CONSIDERATION



Also consider the **Model 6430** Sub-femtoamp Remote SourceMeter SMU Instrument or **Model 2635B** System SourceMeter SMU Instrument for ultimate low current measurements and throughput in the lab or automated testing system.

See pages 98 or 88

TOOLS FOR THE CUSTOMER

 Data Sheet

FOR MORE INFO VISIT
TEK.COM/KEITHLEY-SOURCE-MEASURE-UNITS/SMU-2450-60-GRAPHICAL-SOURCEMETER

3 Reasons to Buy this Product

- 1 Increased R&D productivity. Take advantage of the Model 2450/2460/2461 touchscreen graphical user interface and lower learning curve. Perfect for users new to SMU instruments or for the experienced user who desires best-in-class usability.
- 2 The Model 2450/2460/2461 offers greater performance with time-tested analog accuracy, sensitivity, and measurement results across a wide range of precision I-V and resistance applications.
- 3 Keithley is the trusted name for SMU instruments. The Model 2450/2460/2461 enables the user to learn faster, work smarter, and invent easier.